



VMDSEMI

VUDA002R85APA

Datasheet

General Description

VUDA002R85APA MOSFET is based on unique device design to achieve low $R_{DS(ON)}$, ESD Protected Up to 2.0KV (HBM).

Symbol

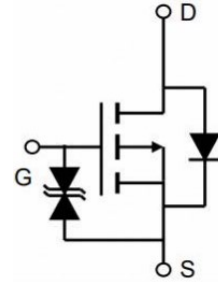


Figure 1 Symbol of VUDA002R85APA

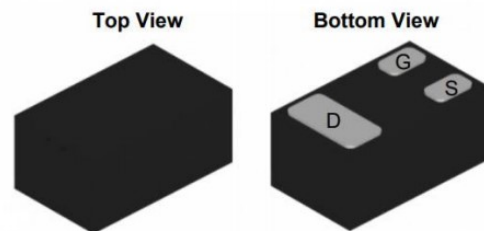
Features

- $R_{DS(ON)_{max}} = 850.0m\Omega @ V_{GS} = -4.5V$
- $R_{DS(ON)_{max}} = 1200.0m\Omega @ V_{GS} = -2.5V$
- Trench Power LV MOSFET technology
- High Density Cell Design for Low $R_{DS(ON)}$
- High Speed switching

Application

- Power management
- Interfacing, Logic switch
- Load Switch

Package Type



DFN1006-3L

Figure 2 Package Type of VUDA002R85APA

Ordering Information

Product Name	Package
VUDA002R85APA	DFN1006-3L

Absolute Maximum Ratings ($T_A = 25\text{ }^\circ\text{C}$, unless otherwise specified)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DSS}	-20	V
Gate-Source Voltage	V_{GSS}	± 12	V
Continuous Drain Current $T_A = 25^\circ\text{C}@$ Steady state	I_D	-0.65	A
Continuous Drain Current $T_A = 70^\circ\text{C}@$ Steady state		-0.52	A
Pulsed Drain Current ^{Note1}	I_{DM}	-2.0	A
Total Power Dissipation $T_A = 25^\circ\text{C}$	P_D	0.9	W
Junction Temperature	T_J	150	$^\circ\text{C}$
Storage Temperature	T_{STG}	-55 to 150	$^\circ\text{C}$

Thermal Resistance

Parameter	Symbol	Min	Typ	Max	Unit
Thermal Resistance, Junction-to-Ambient ^{Note2}	$R_{\theta JA}$		138		$^\circ\text{C}/\text{W}$

Notes :

1. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$.
2. The value of $R_{\theta JA}$ is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$. The Power dissipation P_D is based on $R_{\theta JA}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design, and the maximum temperature of 150°C may be used if the PCB allows it to.

Electrical Characteristics ($T_J = 25\text{ }^\circ\text{C}$, unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Statistic Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D = -250\mu A$	-20			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -20V, V_{GS}=0V$ $T_C = 25\text{ }^\circ\text{C}$			-1	μA
Gate-Body Leakage Current	I_{GSS1}	$V_{GS} = \pm 10V, V_{DS} = 0V$		± 1.5	± 10	μA
	I_{GSS2}	$V_{GS} = \pm 8V, V_{DS} = 0V$		± 0.5	± 2	μA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D = -250\mu A$	-0.35	-0.62	-1.2	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = -4.5V, I_D = 0.5A$		580	850	mΩ
		$V_{GS} = -2.5V, I_D = 0.3A$		855	1200	
		$V_{GS} = -1.8V, I_D = 0.2A$		1350	2000	
Dynamic Characteristics ^{Note2}						
Input Capacitance	C_{ISS}	$V_{DS} = -10V$		71		pF
Output Capacitance	C_{OSS}	$V_{GS}=0V$		20		pF
Reverse Transfer Capacitance	C_{RSS}	$f=1MHz$		15		pF
Gate Resistance	R_g	$f=1\text{ MHz, Open drain}$		85		Ω
Switching Parameters ^{Note2}						
Gate to Source Charge	Q_{gs}	$V_{DS} = -10V$		0.37		nC
Gate to Drain Charge	Q_{gd}	$V_{GS} = -4.5V$		0.27		
Gate Charge Total	Q_g	$I_D = -0.5A$		1.24		
Reverse Recovery Charge	Q_{rr}	$I_F = -0.5A$		0.97		nC
Reverse Recovery Time	t_{rr}	$di/dt = -20A/\mu s$		26		ns
Turn-on Delay Time	$t_{d(on)}$	$V_{DD} = -10V$		4		
Turn-on Rise Time	t_r	$V_{GS} = -4.5V$		19		
Turn-off Delay Time	$t_{d(off)}$	$R_L = 2.5\Omega$		16		
Turn-off Fall Time	t_f	$R_{GEN} = 3\Omega$		25		
Diode Characteristics						
Diode Forward Voltage ^{Note3}	V_{SD}	$V_{GS}=0V, I_S = -0.65A$		-0.8	-1.2	V
Maximum Body-Diode Continuous Current	I_S				-0.65	A

Typical Performance Characteristics

Figure 3: Transfer Characteristics

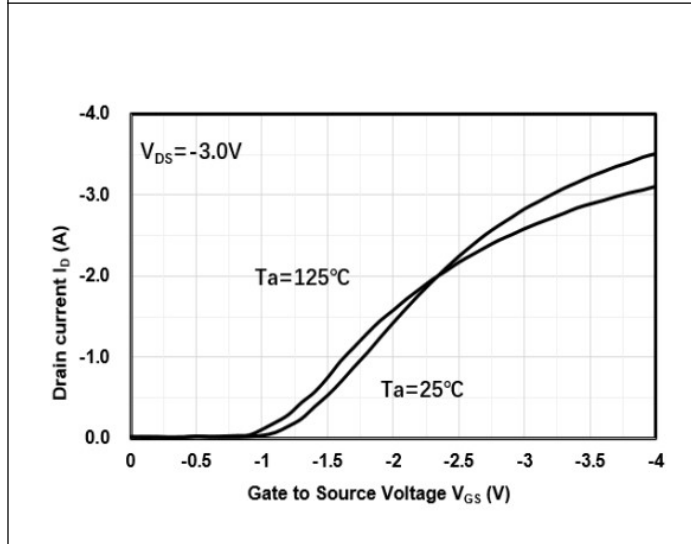


Figure 4: Output Characteristics

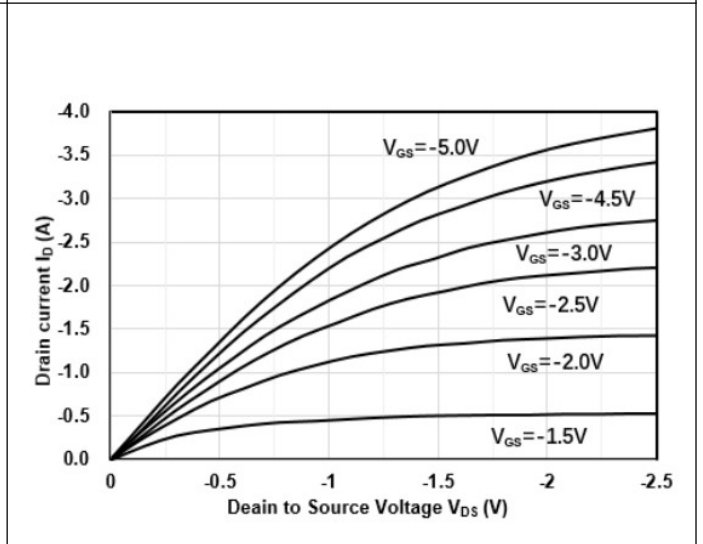


Figure 5: On-Resistance vs. Drain Current and Gate Voltage

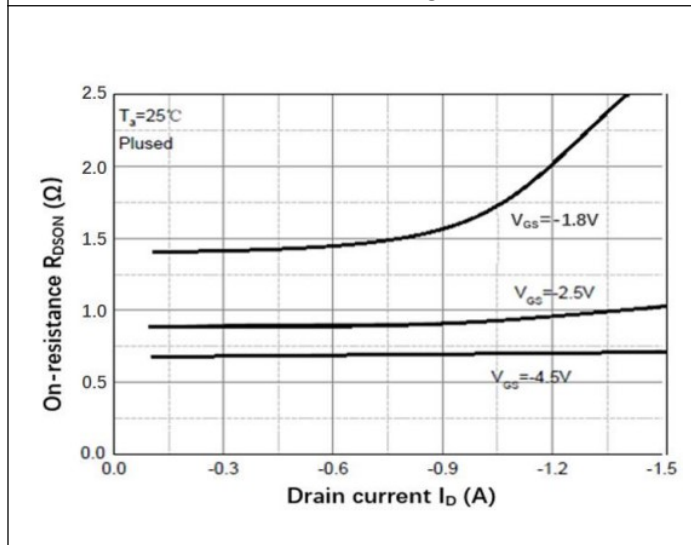


Figure 6: On-Resistance vs. Junction Temperature

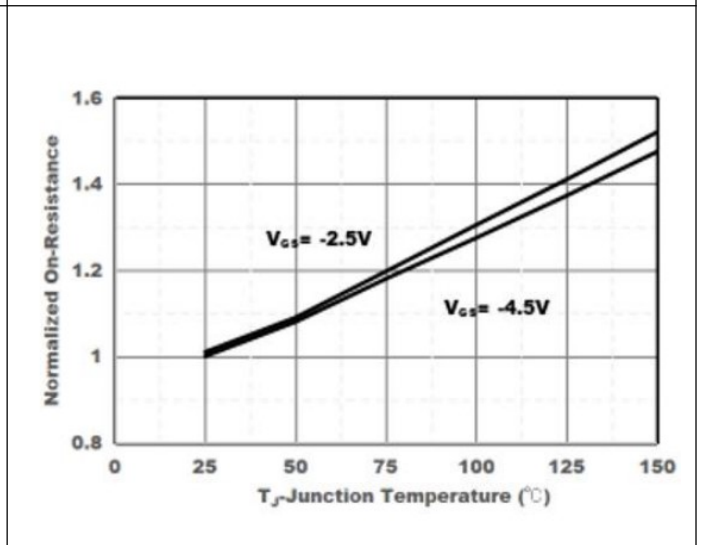


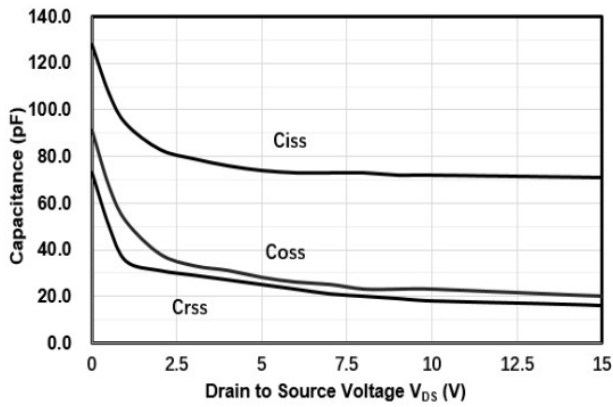
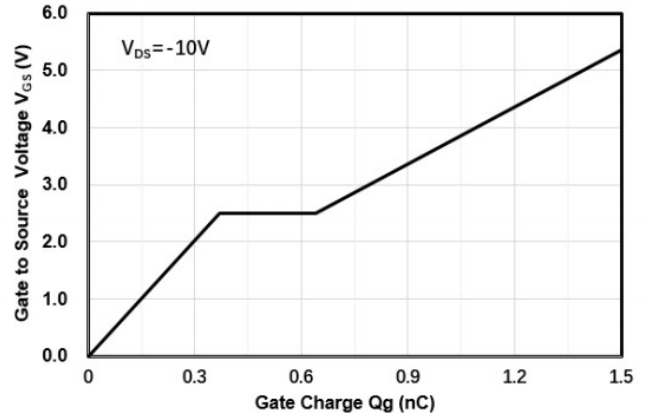
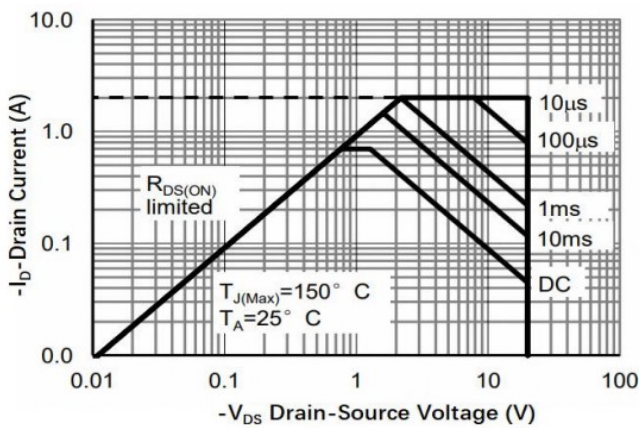
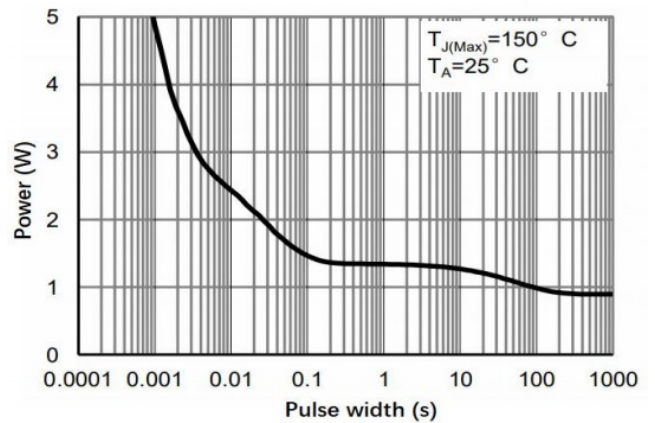
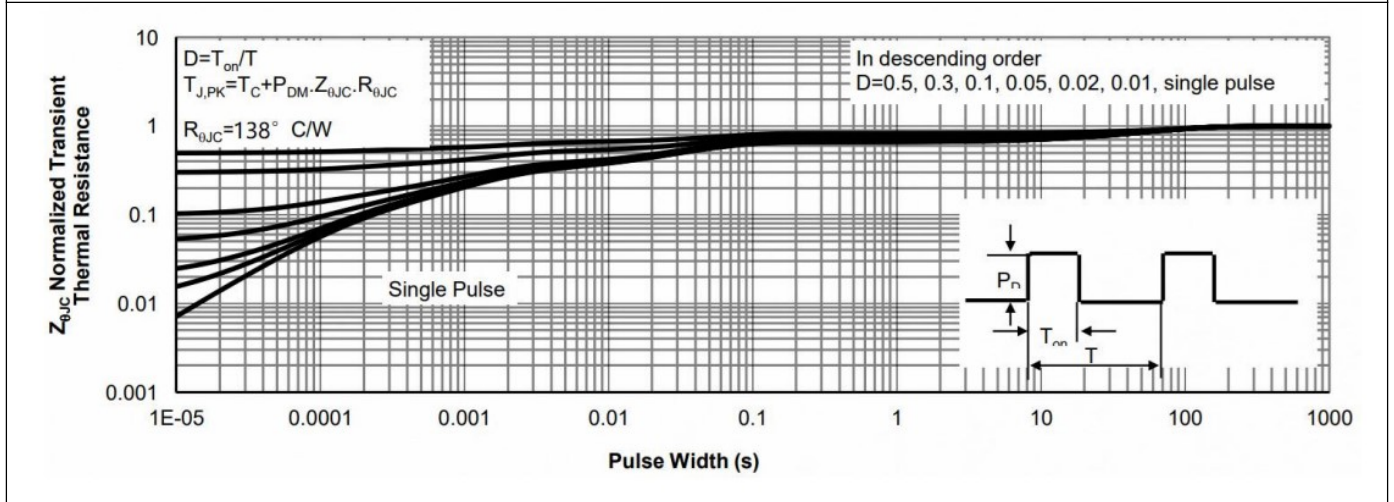
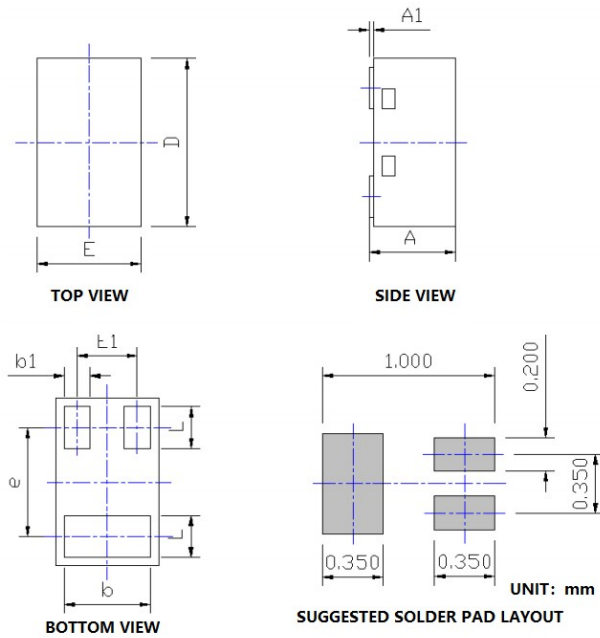
Figure 7: Capacitance Characteristics

Figure 8: Gate Charge

Figure 9: Safe Operation Area

Figure 10: Pulse Power Rating Junction-to-Ambient


Figure 11: Normalized Maximum Transient Thermal Impedance



Mechanical Dimensions:


Symbol	Dimensions (Unit:mm)		
	Min.	TYP.	Max.
A	0.42	--	0.55
A1	0.025REF		
b	0.45	0.50	0.55
b1	0.10	0.15	0.20
D	0.95	1.00	1.05
E	0.55	0.60	0.65
E1	0.35BSC		
e	0.65BSC		
L1	0.20	0.25	0.30

Note:

1. Package body sizes exclude lead burrs.
2. Tolerance 0.1mm unless otherwise specified.
3. The pad layout is for reference purposes only.

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